

<b>Notice of References Cited</b>	Application/Control No. 10/650,038	Applicant(s)/Patent Under Reexamination HAISCH ET AL.	
	Examiner Arnel C. Lavarias	Art Unit 2872	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,721,590	04-2004	Ohishi et al.	600/431
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP 10325798 A	12-1998	Japan	IMAIZUMI et al.	G01N 21/64
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NONE
	V	
	W	
	X	

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